

# <u>AP135N03NF</u>

### **30V N-Channel Enhancement Mode MOSFET**

### Description

The AP135N03NF uses advanced APM-SGT V technology

to provide excellent  $R_{\text{DS}(\text{ON})}\text{,}$  low gate charge and

operation with gate voltages as low as 4.5V. This

device is suitable for use as a Battery protection

or in other Switching application.

### **General Features**

V<sub>DS</sub> = 30V I<sub>D</sub> =135A

 $R_{DS(ON)} < 1.6m\Omega @ V_{GS}=10V (Type: 1.3m\Omega)$ 

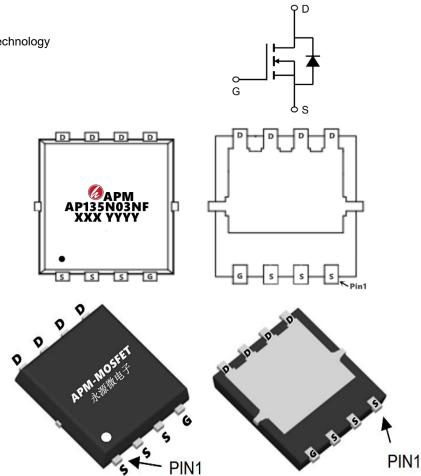
### Application

Boost driver

Brushless motor

BLDC

Clip packaging process



#### Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)	
AP135N03NF	DFN5*6-8L	AP135N03NF XXX YYYY	5000	
Absolute Maximur	। n Ratings (T <sub>c</sub> =25℃unless otherwise r	noted)		
Symbol	Parameter	Rating	Units	
VDS	Drain-Source Voltage	30	V	
VGS	Gate-Source Voltage	±20	V	
ID@TC=25°C	Continuous Drain Current, VGS @ 10V1	135	А	
ID@TC=100°C	Continuous Drain Current, VGS @ 10V1	110	А	
IDM	Pulsed Drain Current2	485	Α	
EAS	Single Pulse Avalanche Energy3	101	mJ	
IAS	Avalanche Current	45	A	
PD@TC=25°C	Total Power Dissipation4	78	W	
TSTG	Storage Temperature Range	-55 to 150	℃	
TJ	Operating Junction Temperature Range	-55 to 150	°C	
R0JA	Thermal Resistance Junction-Ambient 1	25	°C/W	
R0JC	Thermal Resistance Junction-Case1	1.2 °C/W		



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### Electrical Characteristics (TJ=25°C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit	
BVDSS	Drain-Source Breakdown Voltage	$V_{GS}$ =0V , I <sub>D</sub> =250uA	30	36		V	
RDS(ON)	Static Drain-Source On-Resistance <sup>2</sup>	$V_{GS}$ =10V , I <sub>D</sub> =20A		1.3	1.6	1.6 3.0 mΩ	
		V <sub>GS</sub> =4.5V , I <sub>D</sub> =15A		2.0	3.0		
VGS(th)	Gate Threshold Voltage	$V_{GS}$ = $V_{DS}$ , $I_D$ =250uA	1.2	1.7	2.5	V	
IDSS	Drain-Source Leakage Current	V <sub>DS</sub> =30V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			- 1 uA		
IDSS	Drain-Source Leakage Current	V <sub>DS</sub> =30V , V <sub>GS</sub> =0V , T <sub>J</sub> =55℃			5		
IGSS	Gate-Source Leakage Current	$V_{\text{GS}}\text{=}\pm20\text{V}$ , $V_{\text{DS}}\text{=}0\text{V}$			±100	nA	
gfs	Forward Transconductance	V <sub>DS</sub> =5V , I <sub>D</sub> =20A		100		S	
Rg	Gate Resistance	V <sub>DS</sub> =0V , V <sub>GS</sub> =0V , f=1MHz		1.4		Ω	
Qg	Total Gate Charge (4.5V)			39		nC	
Qgs	Gate-Source Charge	V <sub>DS</sub> =20V , V <sub>GS</sub> =4.5V , I <sub>D</sub> =20A		8.6			
Qgd	Gate-Drain Charge			5.0			
Td(on)	Turn-On Delay Time			6.0			
Tr	Rise Time	V <sub>DD</sub> =20V , V <sub>GS</sub> =10V ,		9.0			
Td(off)	Turn-Off Delay Time	$R_G=3\Omega$ , $I_D=20A$		26		ns	
T <sub>f</sub>	Fall Time			10.0			
Ciss	Input Capacitance			3050			
Coss	Output Capacitance	V <sub>DS</sub> =20V , V <sub>GS</sub> =0V , f=1MHz		2650		pF	
Crss	Reverse Transfer Capacitance			117			
IS	Continuous Source Current <sup>1,5</sup>	$V_G=V_D=0V$ , Force Current			135	А	
VSD	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V , Is=78A , TJ=25℃			1.2	V	

Note :

1. The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.

2. The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq$  2%

3、The EAS data shows Max. rating . The test condition is VDD =32V,VGS =10V,L=0.1mH,IAS =54A

4、The power dissipation is limited by 150°C junction temperature

5. The data is theoretically the same as I D and I DM , in real applications , should be limited by total power dissipation.

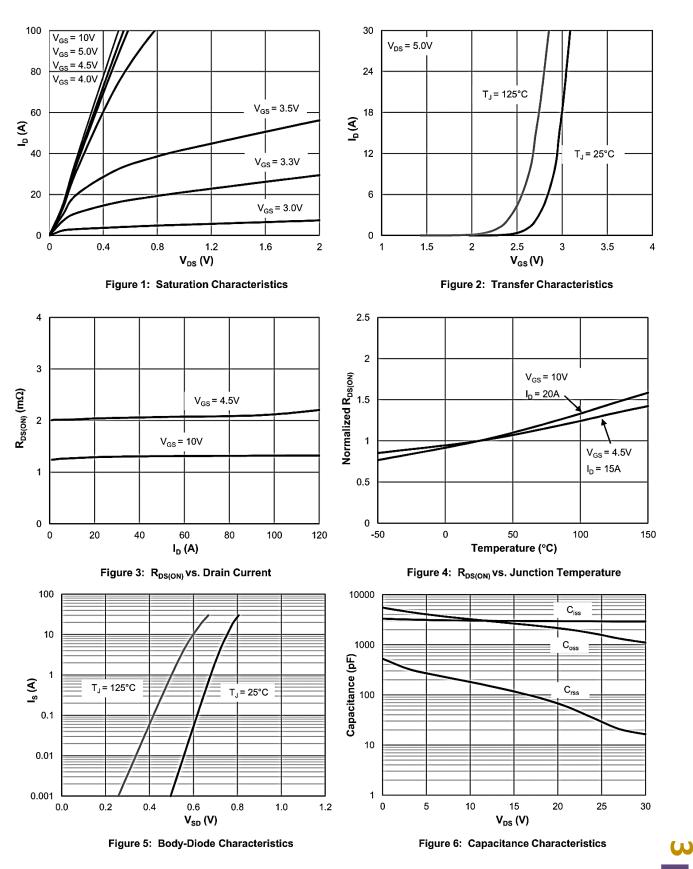
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### **Typical Characteristics**





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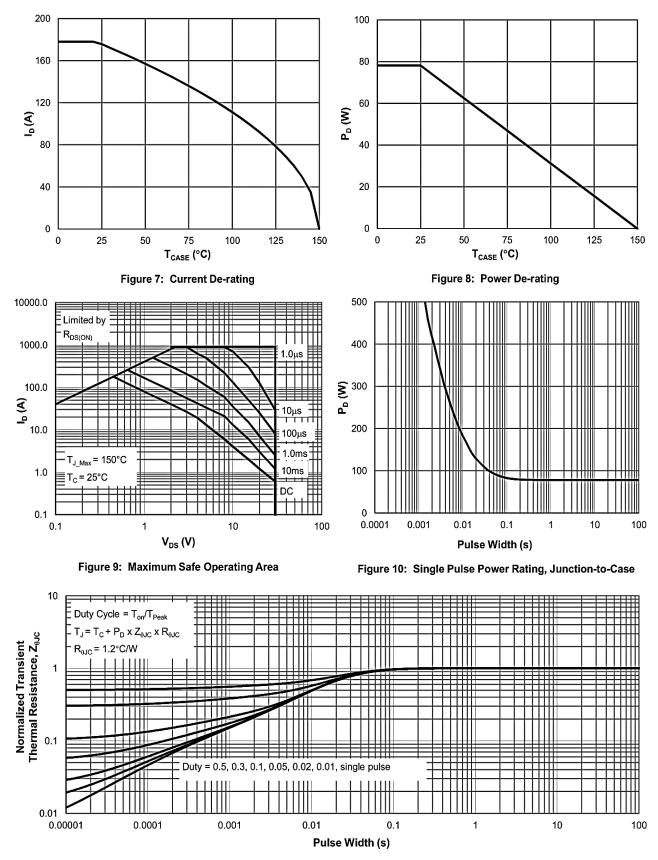
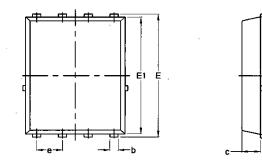


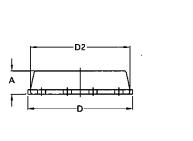
Figure 11: Normalized Maximum Transient Thermal Impedance

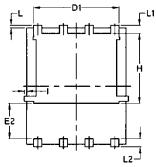


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## Package Mechanical Data-PDFN5\*6-8L-JQ Single







		Com	mon		
Symbol	mm		Inch		
	Mim	Max	Min	Max	
A	1.03	1.17	0.0406	0.0461	
b	0.34	0.48	0.0134	0.0189	
С	0.824	0.0970	0.0324	0.082	
D	4.80	5.40	0.1890	0.2126	
D1	4.11	4.31	0.1618	0.1697	
D2	4.80	5.00	0.1890	0.1969	
E	5.95	6.15	0.2343	0.2421	
E1	5.65	5.85	0.2224	0.2303	
E2	1.60	/	0.0630	/	
е	1.27	' BSC	0.05	BSC	
L	0.05	0.25	0.0020	0.0098	
L1	0.38	0.50	0.0150	0.0197	
L2	0.38	0.50	0.0150	0.0197	
Н	3.30	3.50	0.1299	0.1378	
I	/	0.18	/	0.0070	



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## **30V N-Channel Enhancement Mode MOSFET**

Edition	Date	Change
RVE1.0	2023/2/27	Initial release

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